

Notice of References Cited	Application/Control No. 10/750,624	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
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	N	WO 2001/31439	05-2001	USA	Method and Apparatus for	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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